N3500 Flash Memory Test System

Supported Technologies

- ONFI 3.0
- NAND, eNAND, e2NAND
- eMMC
- SD
- NOR
- MRAM

Resources per Tester Board

- 288 I/O Pins
- 32 DPS Supplies

System Scalability

- N3500e
  - Engineering Lab Chassis
  - Up to 32 Parallel DUTs
- N3500
  - Production Chassis
  - 256 Parallel DUTs
  - 512 Parallel DUTs
  - 640 Parallel DUTs
  - 768 Parallel DUTs
  - 1024 Parallel DUTs
  - up to -
  - 2048 Parallel DUTs

Tanisys Technology

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Lowest Cost of Test

The N3500 is Tanisys Technology’s fourth generation memory test system. Specifically designed for Flash Components and Flash Cards, the N3500 tester-on-a-board architecture targets the broadest range of DUT technologies in various form factors and packages. Each Tester Board (or “Blade”) contains 288 I/O pins and 32 DPS supplies. Up to 64 Blades populated in one test head can test over 2000 DUTs in parallel. Tanisys Technology’s high parallel DUT count architecture, combined with low capital cost, provides the absolute lowest HVM cost of test.

Broatest Technology Coverage

The N3500 Test System target technologies include ONFI 3.0 Devices, NAND, eNAND, SD Protocol Cards, MMC Protocol Cards, NOR, MRAM, and MCP Hybrid Devices/Cards. The N3500’s APG is configured for device-specific requirements at test program load-time, enabling the addition of new products as existing technologies evolve and new technologies emerge in the Flash market space. This APG architectural approach also enables the N3500 to address non-advertised, proprietary, and custom product types.
Tanisys Technologies offers functional Out-of-the-Box Test Solutions. Each Test System comes with a Standard Example Test Flow, Open-Source Application Test Code, and a Standard Production Graphical User Interface. The S/W infrastructure is built on a Distributed Network Architecture (DNA2) which provides a network of building blocks for customizing Test/Data Storage Solutions. A Test Flow and GUI, Centralized Data Storage, and Test System may be physically placed at several locations (i.e. Servers) within a global corporate network for unparalleled control of results data and test files.

Turnkey Integration Solutions
Tanisys Technology has a long history of partnering with handler companies to provide turnkey interfacing solutions. Tanisys has worked with virtually all handler companies to deliver integrated test cells. Customers have several options when it comes to mating the N3500 test system with handlers.

N3500 Specifications

<table>
<thead>
<tr>
<th>Minimum Configuration</th>
<th>16 to 32 DUTs</th>
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<tbody>
<tr>
<td>Maximum Configuration</td>
<td>Up to 2048DUTs</td>
</tr>
<tr>
<td>I/O pins per Tester Board</td>
<td>288 I/O’s, max 1GB/s</td>
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<tr>
<td>DUT Power Supplies Per Tester Board</td>
<td>32 DPS’s</td>
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<tr>
<td>Test Application Development</td>
<td>C++</td>
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<tr>
<td>Input Power</td>
<td>120-240V AC – 50 to 60HZ</td>
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<tr>
<td>Operating Temperature Range</td>
<td>18 to 28C – Air cooled</td>
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<tr>
<td>Operating Humidity Range</td>
<td>30 to 70%</td>
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